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June 2014

FDMC8622

N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 16 A, 56 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 56 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 4 \text{ A}$
- Max $r_{DS(on)} = 90 \text{ m}\Omega$ at $V_{GS} = 6 \text{ V}$, $I_D = 3 \text{ A}$
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability in a widely used surface mount package
- 100% UIL Tested
- Termination is Lead-free and RoHS Compliant

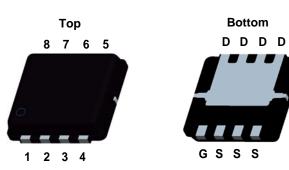


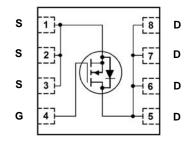
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that incorporates Shielded Gate technology. This process has been optimized for $r_{DS(on)}$, switching performance and ruggedness.

Application

■ DC-DC Primary Switch





MLP 3.3X3.3

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage			100	V
V_{GS}	Gate to Source Voltage			±20	V
I _D	Drain Current -Continuous	$T_C = 25 ^{\circ}C$		16	
	-Continuous	Ta = 25 °C	(Note 1a)	4	Α
	-Pulsed		(Note 4)	30	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	37	mJ
D	Power Dissipation	T _C = 25 °C		31	W
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1a)	2.3	VV
T _J , T _{STG}	Operating and Storage Junction Temperat	ure Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	4.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8622	FDMC8622	MLP 3.3X3.3	13 "	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		69		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μΑ
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	2.9	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-9		mV/°C
		V _{GS} = 10 V, I _D = 4 A		43.7	56	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 3 \text{ A}$		59.9	90	mΩ
()		$V_{GS} = 10 \text{ V}, I_D = 4 \text{ A}, T_J = 125 ^{\circ}\text{C}$		76.4	98	
9 _{FS}	Forward Transconductance	V _{DD} = 10 V, I _D = 4 A		8.9		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 50.V.V 0.V	302	402	pF
C _{oss}	Output Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	72.5	96	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1011 12	4.2	6	pF
R_a	Gate Resistance		1.0		Ω

Switching Characteristics

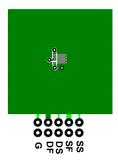
t _{d(on)}	Turn-On Delay Time		5.9	12	ns
t _r	Rise Time	$V_{DD} = 50 \text{ V}, I_D = 4 \text{ A},$	1.6	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	10.2	18	ns
t _f	Fall Time		2.2	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V _{GS} = 0 V to 10 V	5.2	7.3	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$ $V_{DD} = 50 \text{ V},$ $I_{D} = 4 \text{ A}$	3.0	4.1	nC
Q_{gs}	Total Gate Charge	1 _D = 4 A	1.4		nC
Q_{gd}	Gate to Drain "Miller" Charge		1.4		nC

Drain-Source Diode Characteristics

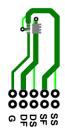
V _{SD} Source to Drain Diode Forward Vo	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 4 \text{ A}$	(Note 2)	0.8	1.3	V
	Source to Drain blode Forward voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.7 \text{ A}$	(Note 2)	0.8	1.2	V
t _{rr}	Reverse Recovery Time	I _F = 4 A, di/dt = 100 A/μs		36	57	ns
Q _{rr}	Reverse Recovery Charge			28	45	nC

NOTES:

^{1.} R_{0,1A} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,1C} is guaranteed by design while R_{0,1C} is determined by the user's board design.



a. 53°C/W when mounted on a 1 in² pad of 2 oz copper



 b. 125 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. Starting T $_{J}$ = 25 °C; N-ch: L = 3.0 mH, I $_{AS}$ = 5.0 A, V $_{DD}$ = 100 V, V $_{GS}$ = 10 V.
- 4. Pulse Id refers to Figure.11 Forward Bias Safe Operation Area.

Typical Characteristics T_J = 25°C unless otherwise noted

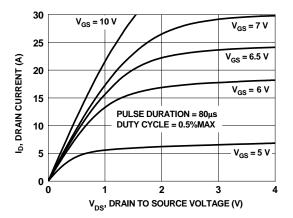


Figure 1. On-Region Characteristics

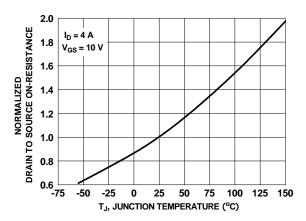


Figure 3. Normalized On-Resistance vs Junction Temperature

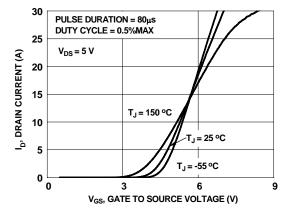


Figure 5. Transfer Characteristics

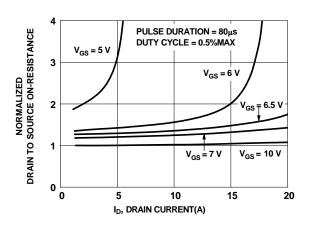


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

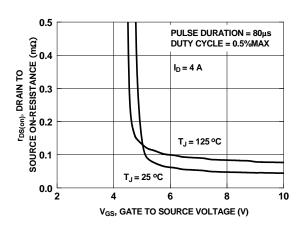


Figure 4. On-Resistance vs Gate to Source Voltage

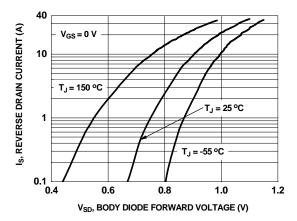


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

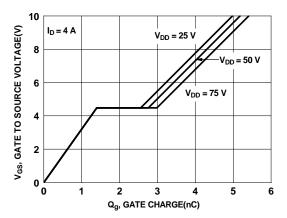


Figure 7. Gate Charge Characteristics

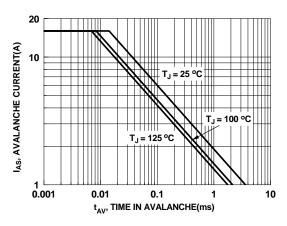


Figure 9. Unclamped Inductive Switching Capability

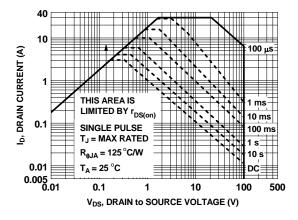


Figure 11. Forward Bias Safe Operating Area

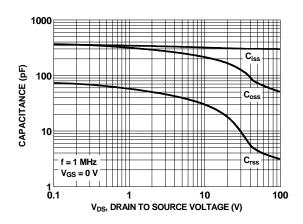


Figure 8. Capacitance vs Drain to Source Voltage

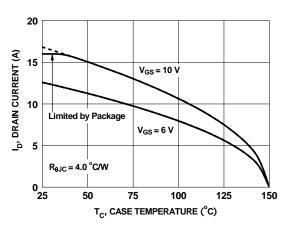


Figure 10. Maximum Continuous Drain Current vs Case Temperature

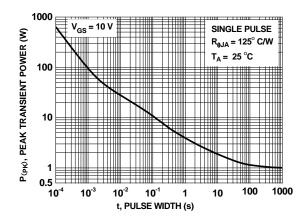


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

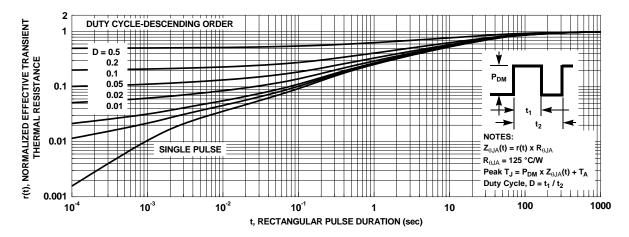
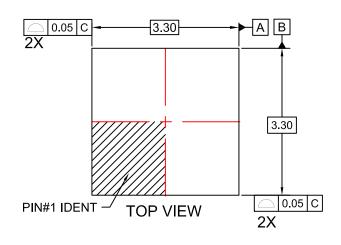
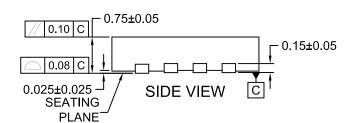
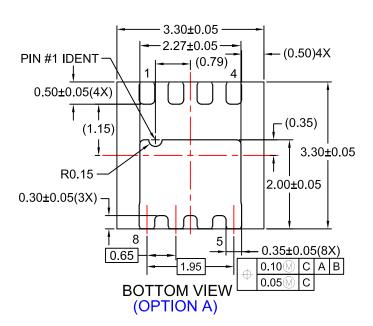
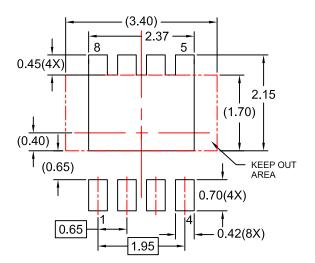


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

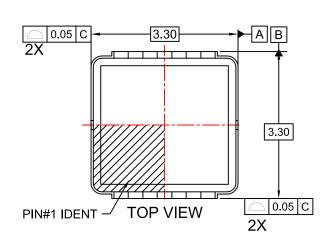


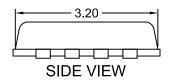


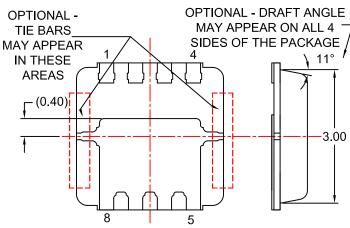




RECOMMENDED LAND PATTERN

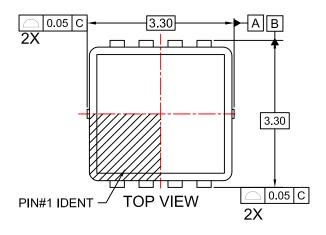


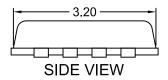


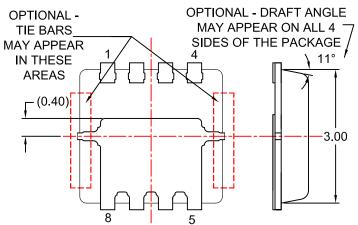


ALL DIMENSIONS AS PER OPTION A
UNLESS SPECIFIED
BOTTOM VIEW
(OPTION B)









ALL DIMENSIONS AS PER OPTION A
UNLESS SPECIFIED
BOTTOM VIEW
(OPTION C)

NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-240.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN
- E. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. BURRS OR MOLD FLASH SHALL NOT EXCEED 0.10MM.
- F. DRAWING FILENAME: MKT-MLP08Wrev3.
- G. OPTION A SAWN MLP, OPTIONS B & C PUNCH MLP.



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